## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

**Applicant** 

HINDERLING et al.

Filed

Herewith

TC/A.U.

Examiner

2235-158

Docket No. Customer No.

06449

Confirmation No.

Director of the United States Patent and Trademark Office P.O. Box 1450 Alexandria, Virginia 22313-1450

## **INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith information that the Office may wish to consider in examination of the subject application. The publications are listed on the attached form PTO-1449.

Respectfully submitted,

Βy

George R. Repper

Attorney for Applicants

Registration No. 31,414

ROTHWELL, FIGG, ERNST & MANBECK, p.c.

Suite 800, 1425 K Street, N.W.

Washington, D.C. 20005 Telephone: (202)783-6040

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				Application Number			
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				First Named Inventor	HINDERLING		
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				Examiner Name			
				Confirmation No.			
Sheet	1	of	1	Attorney Docket Number	2235-158		

FOREIGN PATENT DOCUMENTS												
			Foreign Patent Document		Name of Patentee or Applicant of Cited Document		Date of Publication of Cited Document MM-DD-YYYY					
Examiner Initials*	Cite No.1	Office <sup>3</sup> Code	Number <sup>4</sup> Kin (if kr	d <sup>5</sup> nown)				T <sub>e</sub>				
	1	DE	101 28 484	A1	Asahi Optical Co. Ltd		03-21-2002	AB				
	2	EP	0 448 111	A2	Perceptron Inc.		09-25-1991					
	3	wo	01/29576 (abstract only)	Α	PSC Scanning Inc.		04-26-2001	AB				
	4	EP	0 768 542	A1	Topcon Corp.	•	04-16-1997					
	5	wo	03/002939	A1	Robert Bosch GmbH		01-09-2003	AB				
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	7	EP	0 635 729	A1	Nippon Denso Co.		01-25-1995					
•	8	DE	43 16 348	A1	Leica Heerbrugg AG		11-17-1994	AB				
Examiner Signature						Date Considered						

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code. <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.